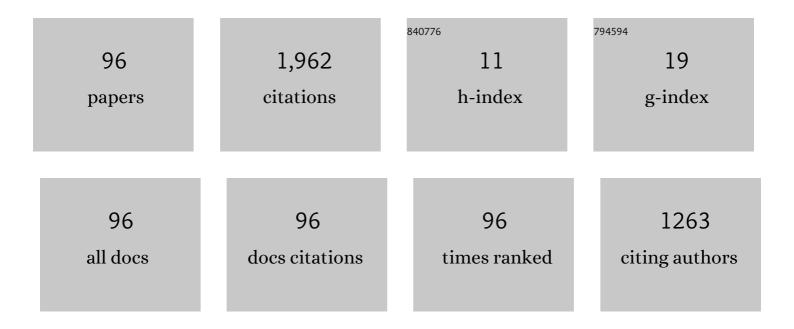


List of Publications by Year in descending order

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20	Modeling TSV open defects in 3D-stacked DRAM. , 2010, , .		22
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29	Pattern-directed circuit virtual partitioning for test power reduction. , 2007, , .		15
30	On Modeling the Lifetime Reliability of Homogeneous Manycore Systems. , 2008, , .		13
31	Online clock skew tuning for timing speculation. , 2011, , .		13
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